Super NiCd Open-Circuit Storage and Low Earth Orbit (LEO) Life Test Evaluation

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Background

- Super NiCd cells studied as potential replacement for existing conventional NiCd designs in Air Force programs
 - Lack of Air Force test data on larger cell sizes
 - Handling and storage required active charging
- 50 Ah cells manufactured by Eagle-Picher/Colorado Springs
 - Advanced cell design with improved separator material and electrode making processes
 - Used in several NASA and commercial programs
 - Handling and storage required active charging
 - Three 5-cell packs on test with variations in temperature
 - Initial open-circuit periods to simulate worst case handling
 - Life tests follow characterization and charged



Background (Cont'd)

- open-circuit storage
- NASA funded testing at Crane/NSWC (as part of a joint NASA/Air Force program)
- Purpose of testing
 - To evaluate the impact of various periods of charged, opencircuit storage on the initial and cycle life performance
 - To evaluate the life capabilities for generic cell qualification in Air Force programs



Test Plan

- Initial characterization tests: 10°C, 20°C and 30°C capacity; 0°C overcharge; and 20°C impedance, charge retention, charge efficiency and 24 hour voltage recovery
- Charged, open-circuit storage tests:
 - Pack 1 (Lot 3) stored at 1, 2 and 3 months at 20°C
 - Pack 2 (Lot 3) stored at 1, 2 and 3 months at 0°C
 - Pack 3 (Lot 2) stored at 1, 2, 3 and 6 months at 0°C
 - 20°C and 0°C capacities measured prior to first storage period and after each storage period
- Post storage characterization tests (same as initial)
- Accelerated LEO life tests at 40% DoD
 - Pack 1 at 20°C
 - Packs 2 and 3 at 0°C



Initial Characterization Tests

The average cell values - pre storage tests:
 (in Ah, unless otherwise noted)

	10°C	20°C	30°C	0°C Ovch.	20°C Imp.	20°C Ch Ret
Pack 1	55.6	52.5	52.3	57.7	52.0	91.2%
Pack 2	54.9	52.0	51.2	56.5	51.6	90.2%
Pack 3	48.3	49.1	49.7	48.2	49.2	88.2%



Open-Circuit Storage Tests

- Comparison of capacities after charged, open-circuit stand to their pre-30-day open-circuit values:
 - Pack 1 at 20°C: 80.7% after 30-day-period to 72.1% after 90day-period
 - Pack 2 at 0°C: 88.9% after 30-day-period to 85.4% after 90day-period
 - Pack 3 at 0°C: 85.6% after 30-day-period to 70.9% after 180day-period
 - Ave capacity at 0°C: 87.3% after 30-day-period to 70.9% after 180-day-period

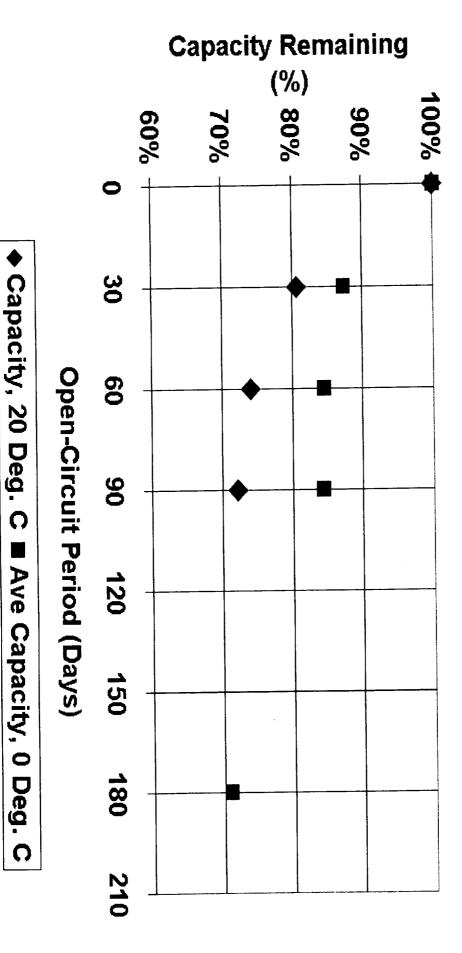


Open-Circuit Storage Tests

- Comparison of capacities after charged, open-circuit stand to their pre-30-day open-circuit values:
 - Pack 1 at 20°C: 80.7% after 30-day-period to 72.1% after 90- day period
 - Pack 2 at 0°C: 88.9% after 30-day-period to 85.4% after 90day period
 - Pack 3 at 0°C: 85.6% after 30-day-period to 83.0% after 90day period to 70.9% after 180-day period
 - Ave capacity at 0°C: 87.3% after 30-day-period to 84.2% after 90-day period to 70.9% after 180-day period



Capacity after Charged, Open-Circuit Periods



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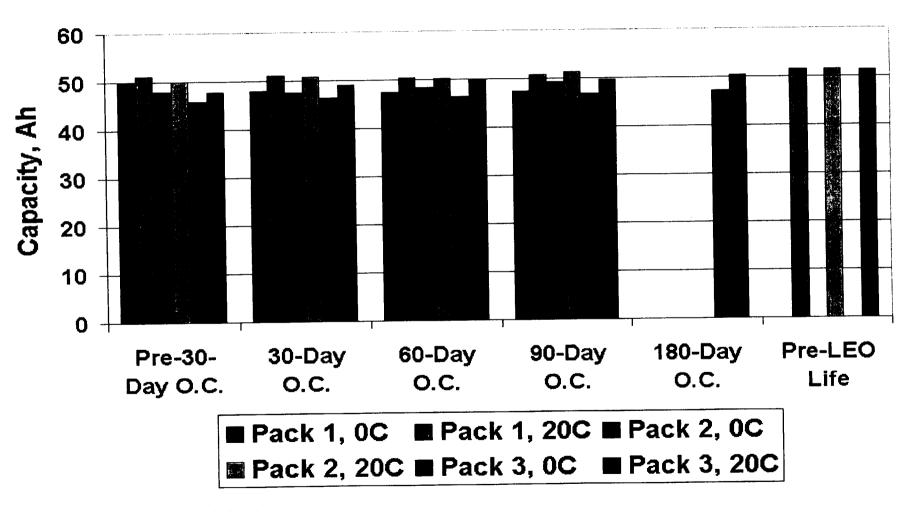


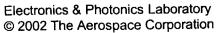
Open-Circuit Storage Tests (Cont'd)

- 0°C and 20°C capacities post open-circuit storage:
 - There is generally a small decrease in capacities post 20°C open-circuit storage (Pack 1)
 - Within 3 Ahrs of pre-30-day storage values
 - Generally, there is a slight increase in capacities post 0 °C open-circuit storage (Pack 2)
 - Within 1.5 Ahrs of pre-30-day storage values
 - There is a small increase in capacities post 0°C open-circuit storage (Pack 3)
 - Within 3 Ahrs of pre-30-day storage values
- Long term impacts need to be assessed



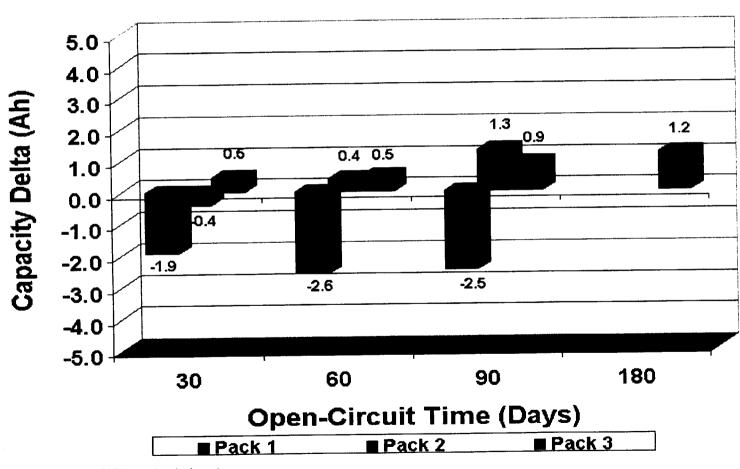
0°C and 20°C Pack Capacities







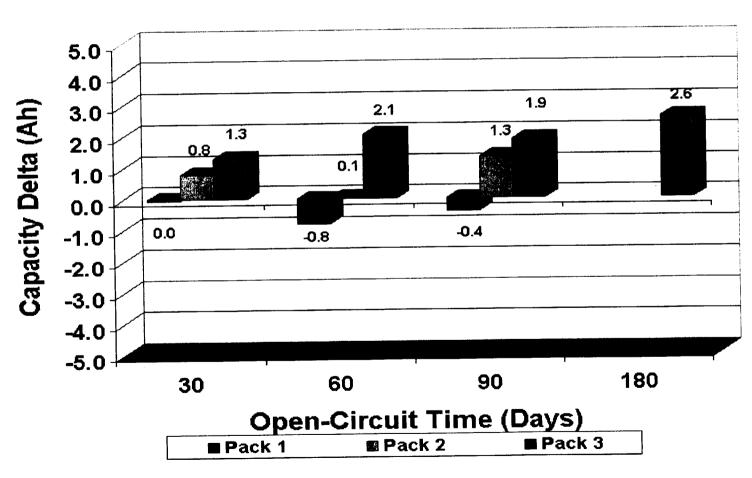
Change in Post Storage Capacity at 0°C With Reference to Pre-30-Day Storage Capacities



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Change in Post Storage Capacity at 20°C With Reference to Pre-30-Day Storage Capacities



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Post Storage Characterization Tests

The average cell values - post storage tests:
 (in Ah, unless otherwise noted)

	10°C	20°C	30°C	0°C Ovch.	20°C Imp.	20°C Ch Ret
Pack 1	51.1	51.6	52.3	50.1	51.3	88.8%
Pack 2	53.5	51.5	51.5	53.4	51.1	92.7%
Pack 3	51.6	51.4	51.9	50.9	51.1	89.6%



Post-Storage Accelerated LEO Life Tests

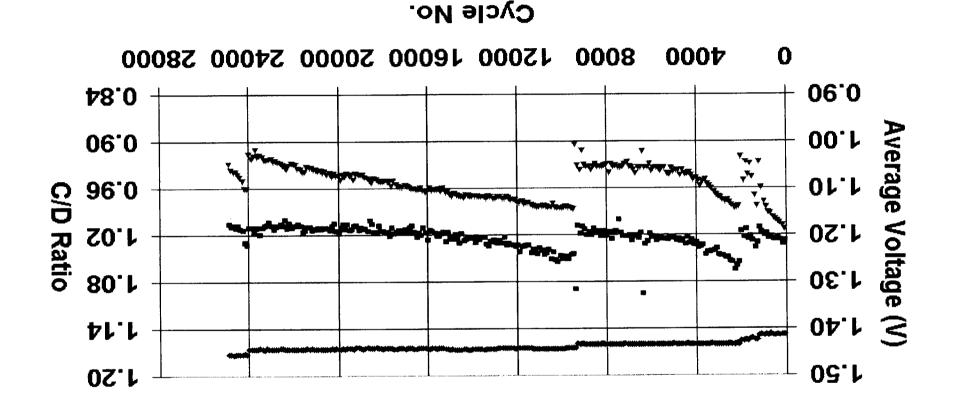
- For each of the three 5-cell packs, a life cycle simulates a 90minute orbit
 - Discharge at 40 A for 0.5 hr, 40% DoD
 - Per initial test plan, failure defined as < 1.0 V/cell
 - Charge at a high-rate current of 40 A, followed by a taper charge for an hour of total duration.
 - Temperature-compensated V/T levels
- Pack 1 consists of five lot 3 cells
 - 20°C test started on 8/11/97
 - Initial V/T = 1.414 V/cell. Incrementally increased to current value of 1.454 V/cell during cycle 24088
 - Low EODVs



Post-Storage Accelerated LEO Life Tests (Cont'd)

- As of 2/8/02, 24900 cycles have been completed.
 - Average EOCV = 1.454 V
 - EOC cell voltage differential = 7.5 mV
 - C/D = 1.005
 - Average EODV = 1.050 V
 - EOD cell voltage differential = 19.2 mV



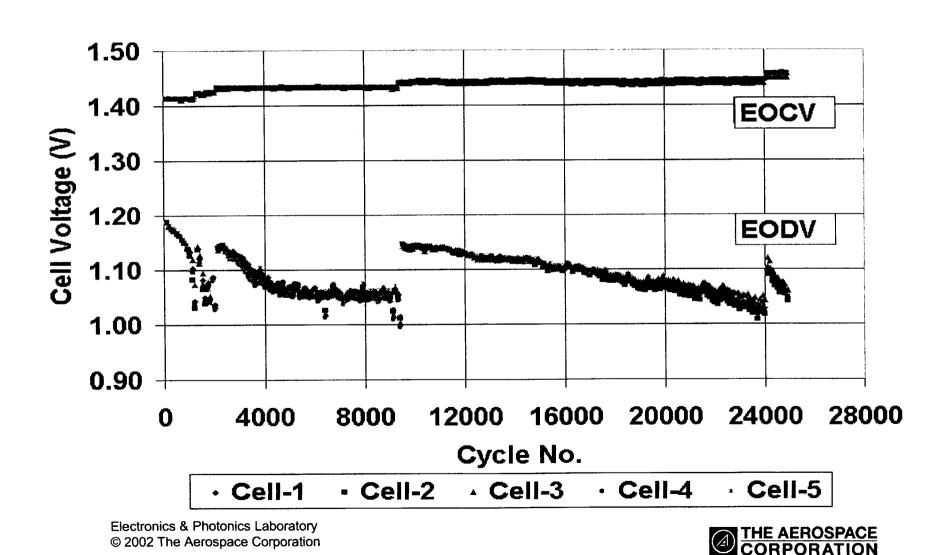


(Pre-Life Storage @ 20°C: 1, 2, 3 Mos.)

Pack 1: Average Voltage and C/D

· EOC Voltage · EOD Voltage · C/D Ratio

Pack 1: EOCV and EODV (Pre-Life Storage @ 20°C: 1, 2, 3 Mos.)

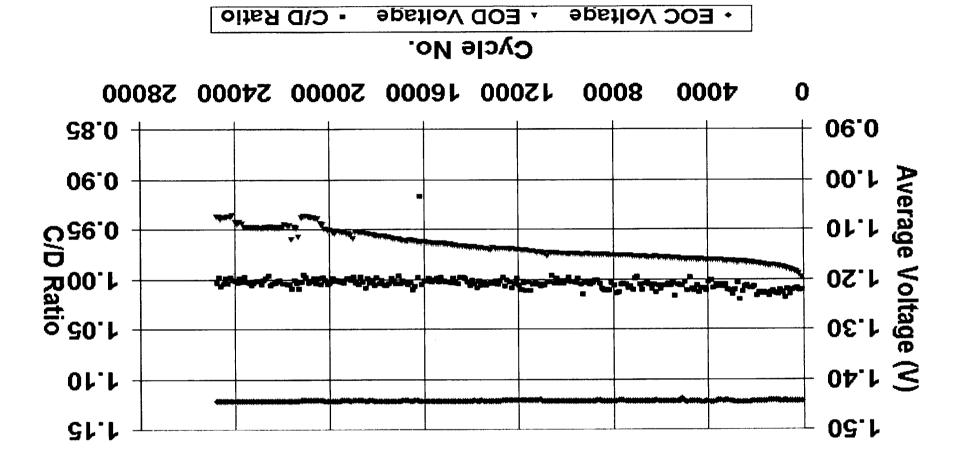


Post-Storage Accelerated LEO Life Tests (Cont'd)

- Pack 2 consists of five lot 3 cells
 - 0°C test started on 8/11/97
 - Initial V/T = 1.444 V/cell, which remains the current limit
 - As of 2/7/02, 24800 cycles have been completed.
 - Average EOCV = 1.443 V
 - EOC cell voltage differential = 2.0 mV
 - C/D = 1.003
 - Average EODV = 1.076 V
 - EOD cell voltage differential = 33.2 mV

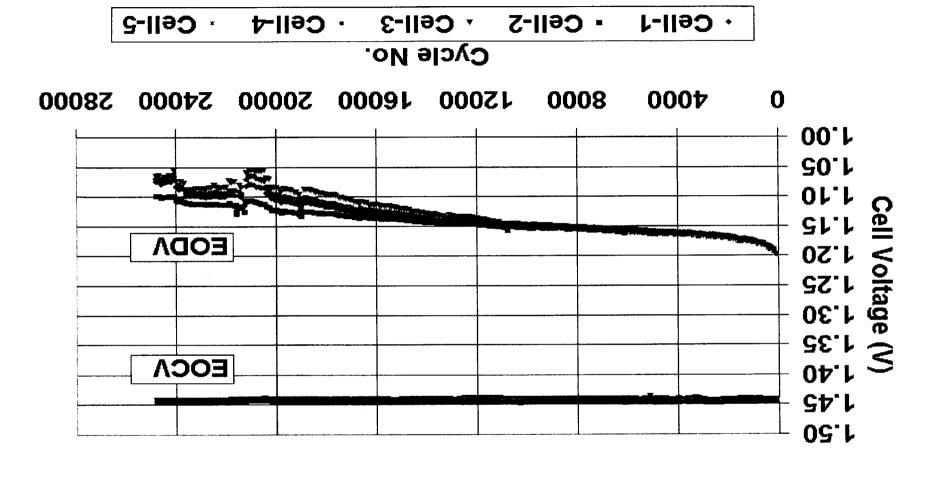


Pack 2: Average Voltage and C/D (Pre-Life Storage @ 0°C: 1, 2, 3 Mos.)









(Pre-Life Storage @ 0° C: 1, 2, 3 Mos.)

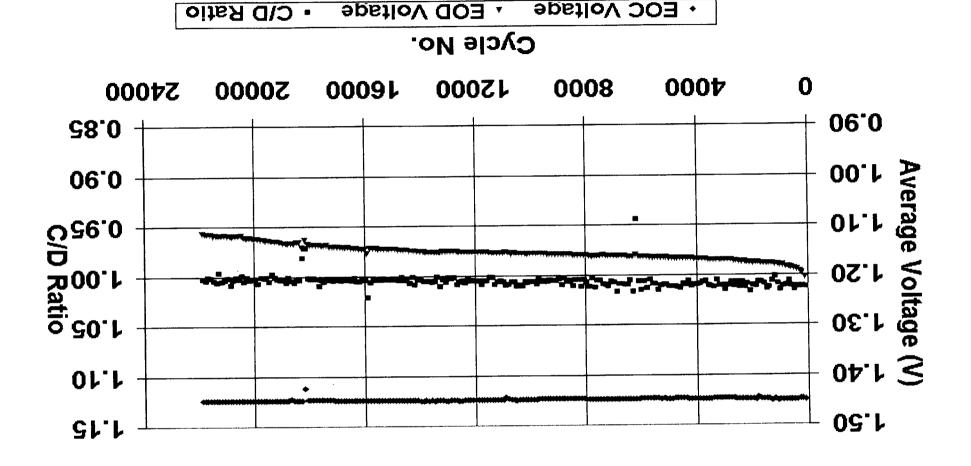
Pack 2: EOCV and EODV

Post-Storage Accelerated LEO Life Tests (Cont'd)

- Pack 3 consists of five lot 2 cells
 - 0°C test started on 2/17/98
 - Initial V/T = 1.444 V/cell. Increased to present value of 1.450
 V/cell during cycle 81
 - Recharge close to, but less than, 100%
 - As of 2/9/02, 21900 cycles have been completed.
 - Average EOCV = 1.449 V
 - EOC cell voltage differential = 3.2 mV
 - C/D = 1.002
 - Average EODV = 1.115 V
 - EOD cell voltage differential = 28.0 mV

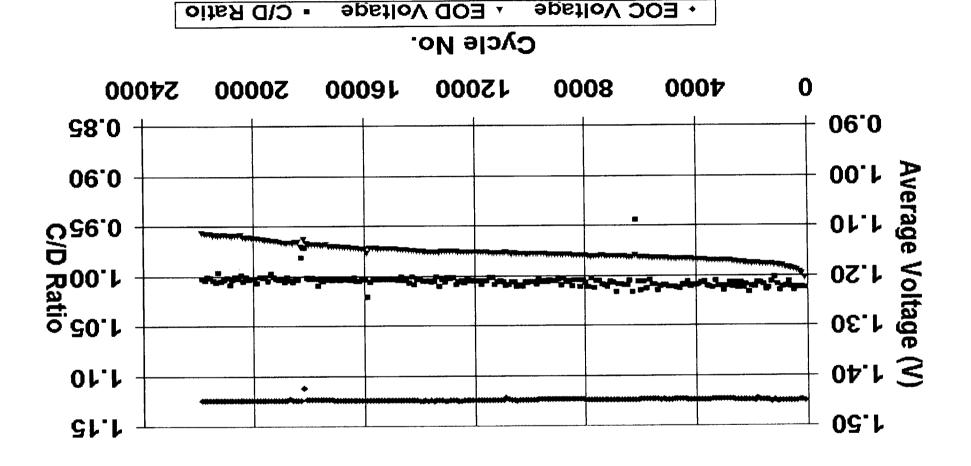


Pack 3: Average Voltage and C/D (Pre-Life Storage @ 0°C: 1, 2, 3, 6 Mos.)



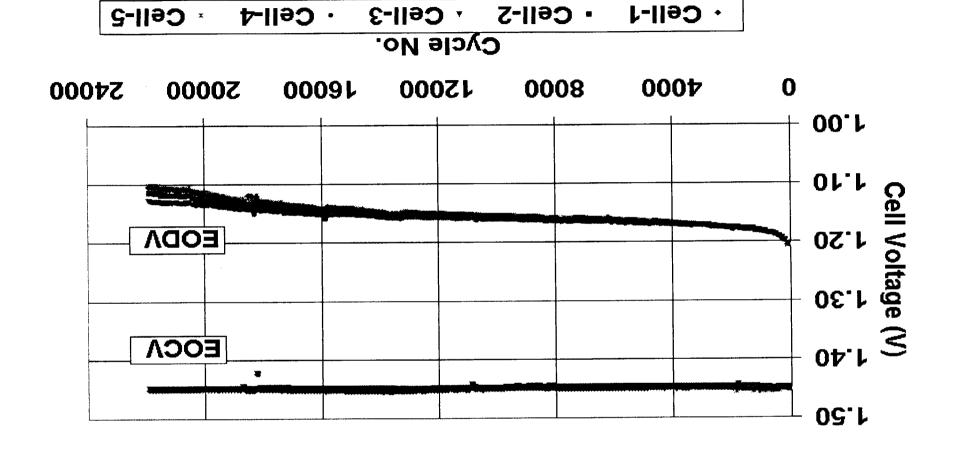


Pack 3: Average Voltage and C/D (Pre-Life Storage @ 0 Deg. C: 1, 2, 3, 6 Mos.)









Summary

- Cycle-life capability supports generic Air Force qualification
 - Conventional LEO mission goal up to 5-year duration
 - Conventional GEO mission goal up to 10-year duration
- Handling and storage may not require active charging
 - Cell manufacturer now provides option of up to 180 days of open-circuit storage with top-off charging every 14 days or less
 - Programs have more flexibility
- Launch site
 - Could eliminate requirement for continuous trickle charge
 - Can result in battery processing cost and time reduction

